Electrical Characterization of Coplanar Waveguides on FlexTrateTM

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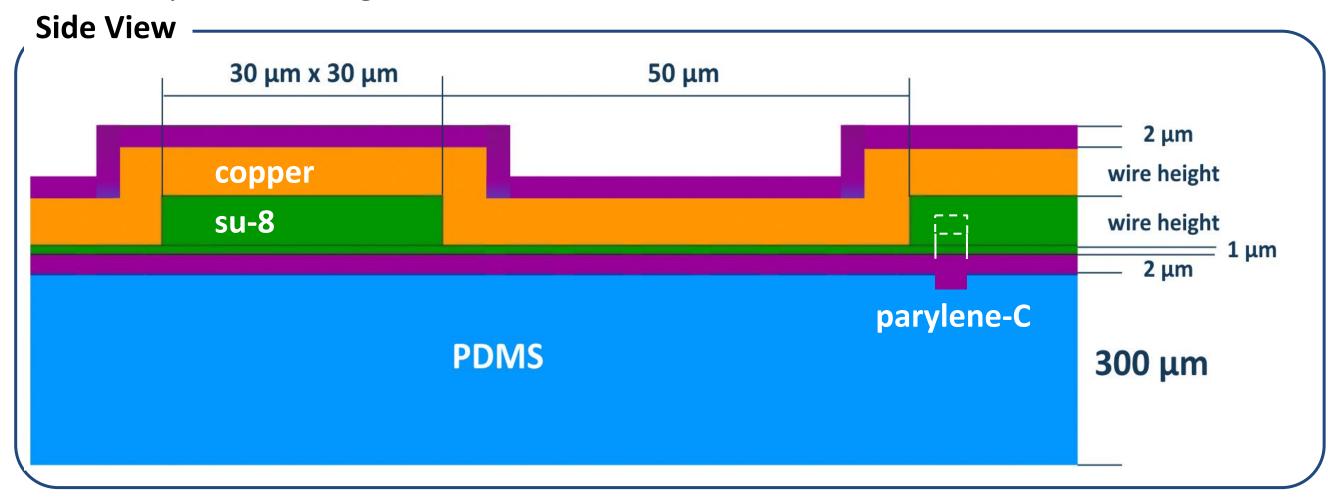
Introduction

Goal: Characterization of electrical characteristics of FlexTrate interconnects up to 5GHz

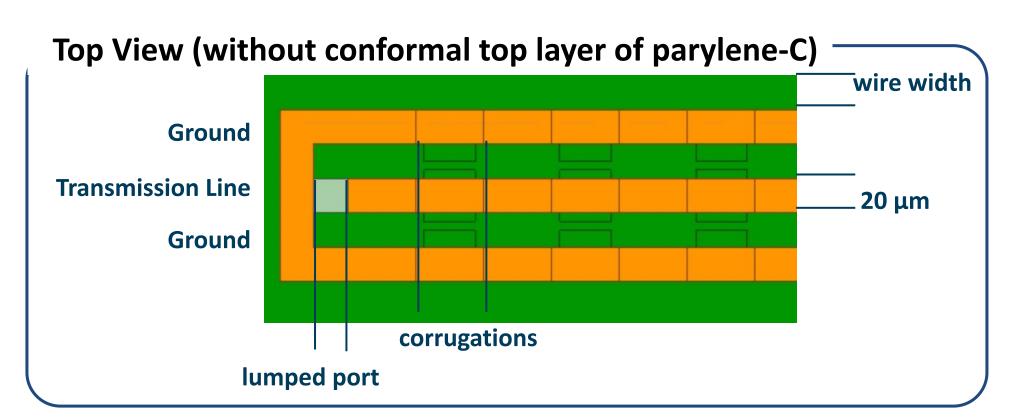
- Simulations conducted using Ansys HFSS
- Samples fabricated and measured to validate simulations
- RLGC characteristics extracted from simulation results

Simulation Set Up

Full 3D Coplanar Waveguide Model in ANSYS HFSS



*not to scale



Wire Width	Wire Height	
2.5 μm	1 μm	
5 μm	1 μm	
10 μm	2.5 μm	
20 μm	5 μm	

Constants Used (determined through research papers/production):

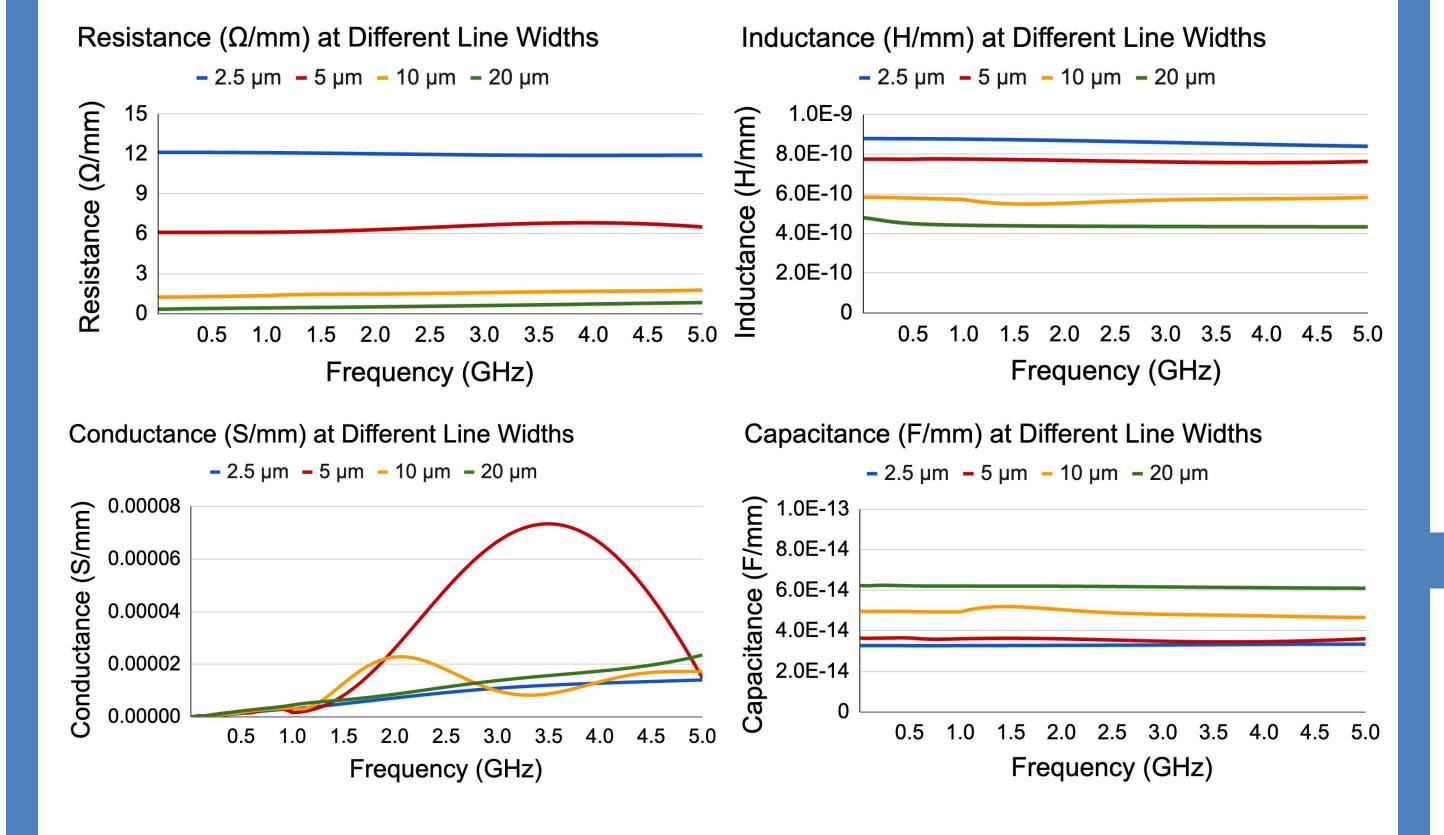
Material	Parylene-C [1]	Su-8 [2]	PDMS [3]
Dielectric Constant (K)	3.1	2.85	2.75
Loss Tangent (tan(δ))	0.001	0.03-0.045	0.0375-0.045

- [1] https://vsiparylene.com/parylene-properties/
- [2] Ayad Ghannam, e.g., EuMC, 2009
- [3] N. J. Farcich, e.g., IEEE Transactions on Microwave Theory and Techniques, 2008

RLGC Results

Script written in Matlab converts Z-parameter simulation results to RLGC:

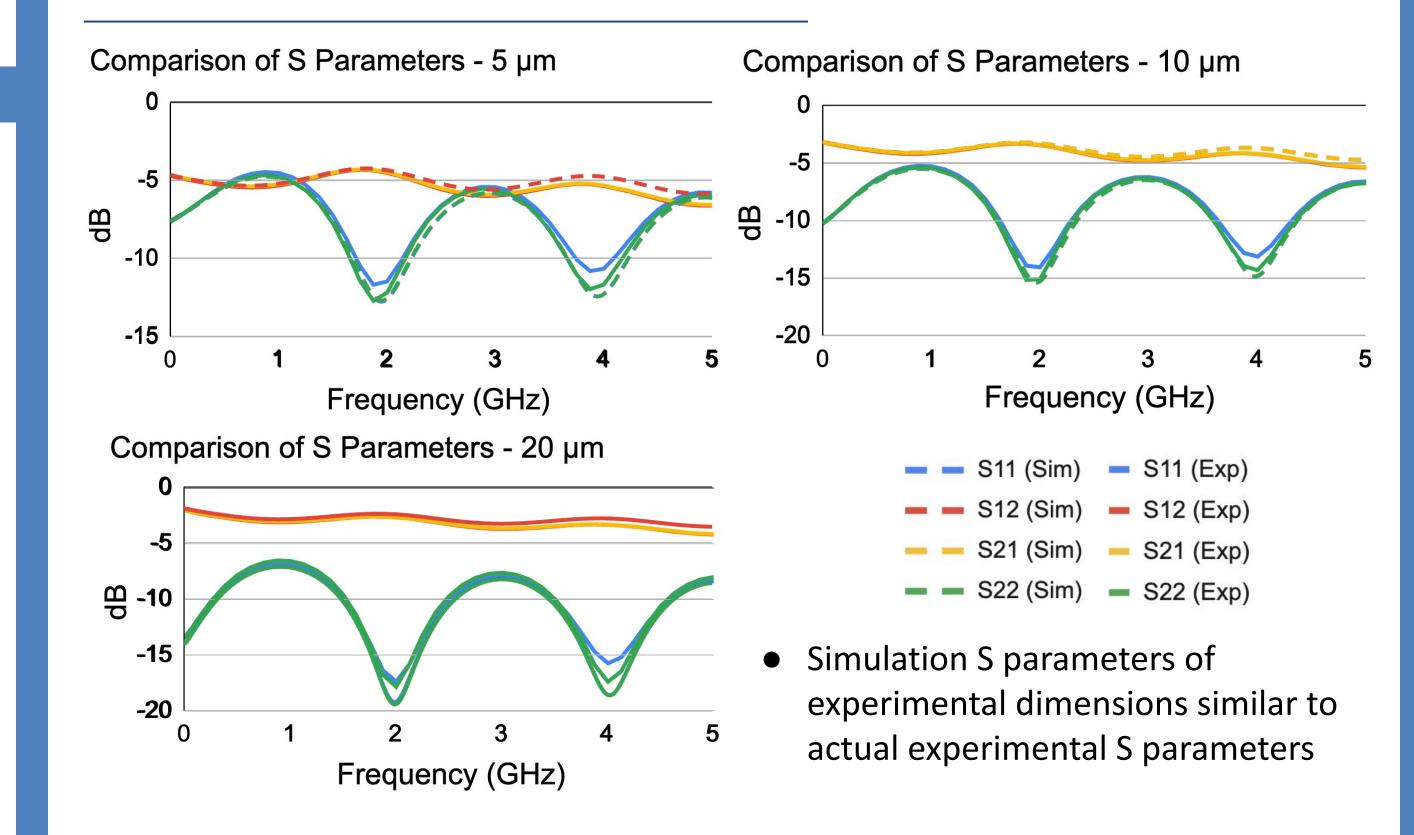
RLGC Graphs for Each Line Width



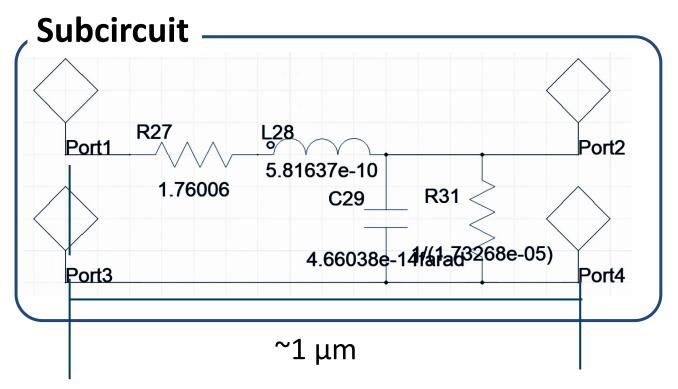
Experimental Validation of Simulations

• Fabricated sample with 5 μ m, 10 μ m, and 20 μ m trace widths, 50 mm trace length, and 20 µm spacing following simulation set up

Simulation vs Experimental S-Parameters



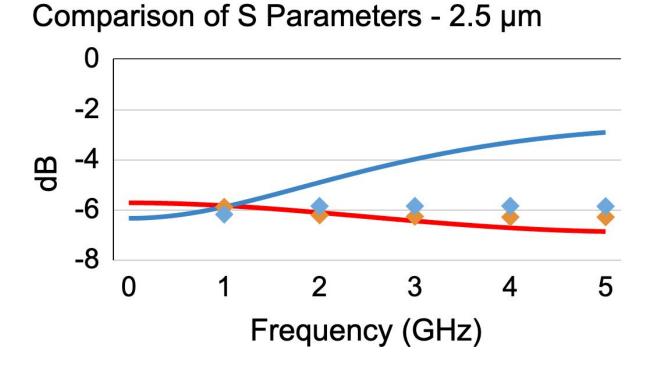
RLGC Verification

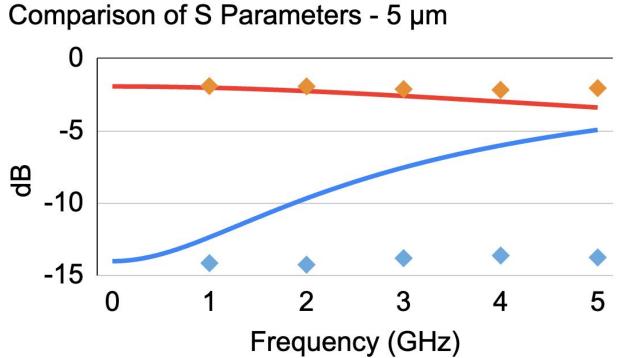


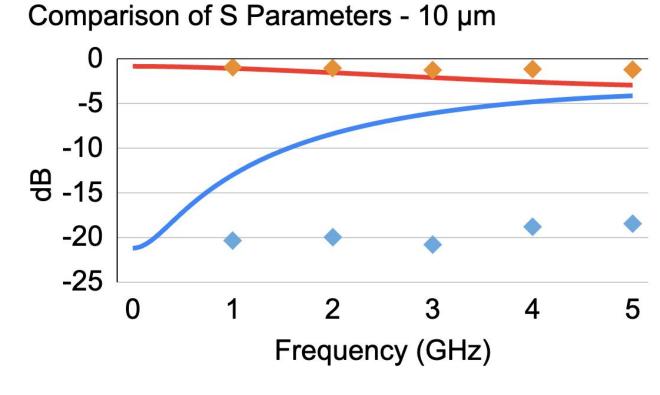
- Subcircuit model of transmission line (~8 μm) with SPICE RLGC circuit in **HFSS**
- Full circuit solved for S-parameters at 1, 2, 3, 4, and 5 GHz for each wire width

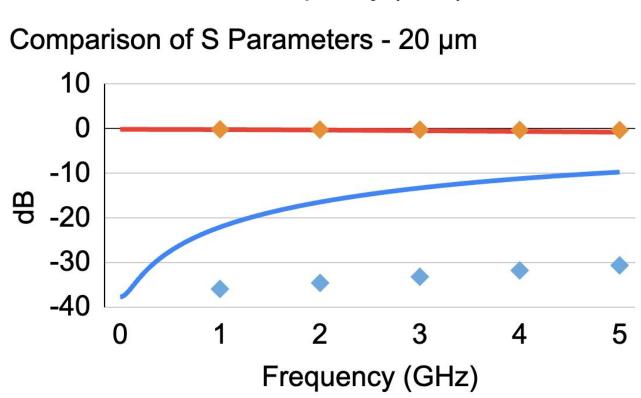
Simulation vs SPICE S-Parameters











- Insertion loss from the simulation is similar to the SPICE model for all line widths
- Return loss from simulation starts around the same value as SPICE model before large deviation

Conclusions and Acknowledgements

- Electrical characteristics of FlexTrate interconnects were extracted from experimentally validated simulation data
- Further investigation into return loss deviation underway

This work is supported by the UCLA CHIPS consortium.

